Power MOSFET

30 V, 41 A, Single N-Channel, SO-8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit	
Drain-to-Source Vol	tage		V _{DSS}	30	V	
Gate-to-Source Volt	age		V_{GS}	±20	V	
Continuous Drain Current R _{0JA}		$T_A = 25^{\circ}C$ $T_A = 100^{\circ}C$	I _D	14 8.7	Α	
(Note 1)		• • •				
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P_{D}	2.6	W	
Continuous Drain		T _A = 25°C	I _D	23	Α	
Current $R_{\theta JA} \le$ 10 s (Note 1)		T _A = 100°C		14.3		
Power Dissipation $R_{\theta JA} \le 10 \text{ s}$ (Note 1)	Steady State	T _A = 25°C	P _D	6.83	V	
Continuous Drain	State	T _A = 25°C	Ι _D	8.3	Α	
Current R _{θJA} (Note 2)		T _A = 100°C		5.2		
Power Dissipation R _{θJA} (Note 2)		T _A = 25°C	P_{D}	0.91	W	
Continuous Drain Current R _{BJC}		T _C = 25°C	Ι _D	41	Α	
(Note 1)		T _C = 85°C		26		
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P_{D}	22.3	W	
Pulsed Drain Current	T _A = 25°	$T_A = 25^{\circ}C, t_p = 10 \ \mu s$		125	Α	
Current Limited by Pa	ackage	T _A = 25°C	I _{Dmax}	100	Α	
Operating Junction a Temperature	Operating Junction and Storage Temperature		T _J , T _{STG}	–55 to +150	°C	
Source Current (Body Diode)		I _S	20	Α		
Drain to Source DV/DT		dV/d _t	8.0	V/ns		
Energy T _{.I} = 25°C, V _I	Single Pulse Drain-to-Source Avalanche Energy T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 25 A_{pk} , L = 0.1 mH, R_G = 25 Ω		E _{AS}	31	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C		

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

1

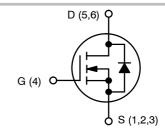


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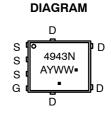
http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	7.2 m Ω @ 10 V	41 A
30 V	11 mΩ @ 4.5 V	417



N-CHANNEL MOSFET

SO-8 FLAT LEAD CASE 488AA STYLE 1



MARKING

A = Assembly Location Y = Year WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4943NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4943NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	5.6	
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	49.1	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	137.2	C/VV
Junction-to-Ambient – (t ≤ 10 s) (Note 3)	$R_{ heta JA}$	18.3	DataShoot

Parameter	Symbol	Test Cond	lition	Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D$	= 250 μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				15		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25°C			1.0	_
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}	_S = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.2	1.66	2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		5.8	7.2	
			I _D = 15 A		5.8		mΩ
		V _{GS} = 4.5 V	I _D = 30 A		8.2	11	
			I _D = 15 A		8.2		
Forward Transconductance	g _{FS}	V _{DS} = 1.5 V, I _D = 15 A			32		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1401		pF
Output Capacitance	C _{OSS}				446		
Reverse Transfer Capacitance	C _{RSS}				16		
Total Gate Charge	Q _{G(TOT)}				9.2		
Threshold Gate Charge	Q _{G(TH)}	\/ 45\/\/	45 \		2.7]
Gate-to-Source Charge	Q_{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$		4.4		nC	
Gate-to-Drain Charge	Q_{GD}				1.9		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} =	15 V; I _D = 30 A		20.9		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				11		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			31		ns
Turn-Off Delay Time	t _{d(OFF)}				18		
					1		7

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

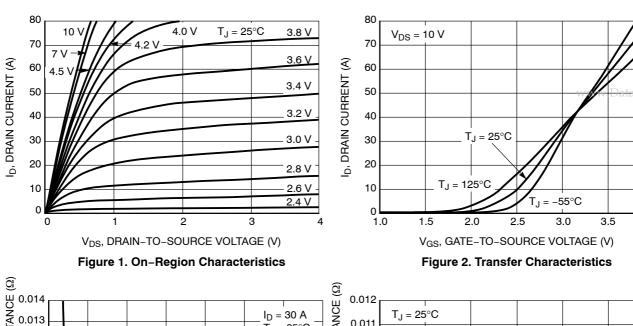
^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

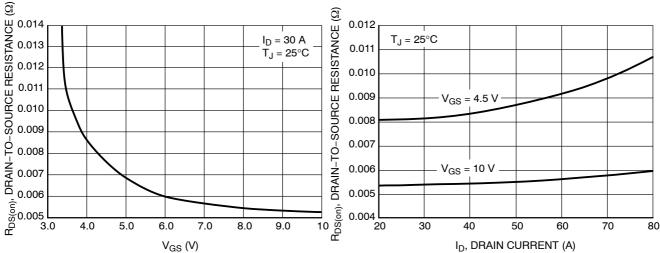
ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (Not	e 6)						
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			8.0		ns DataSheet
Rise Time	t _r				21		
Turn-Off Delay Time	t _{d(OFF)}				21	TAZ TAZ TAZ	
Fall Time	t _f				2.1		
DRAIN-SOURCE DIODE CHARACTER	RISTICS						
Forward Diode Voltage	ward Diode Voltage V_{SD} $V_{GS} = 0 \text{ V}$.	T _J = 25°C		0.9	1.1	.,,	
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$	T _J = 125°C		0.8		- V
Reverse Recovery Time	t _{RR}	,			23		
Charge Time	ta	V _{GS} = 0 V, dIS/dt =	100 A/μs,		12.5		ns
Discharge Time	t _b	I _S = 30 A			10.5]
Reverse Recovery Charge	Q _{RR}				10		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	T _A = 25°C			0.93		nH
Drain Inductance	L _D				0.005		nH
Gate Inductance	L _G				1.84		nH
Gate Resistance	R _G				1.1	2.0	Ω

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS







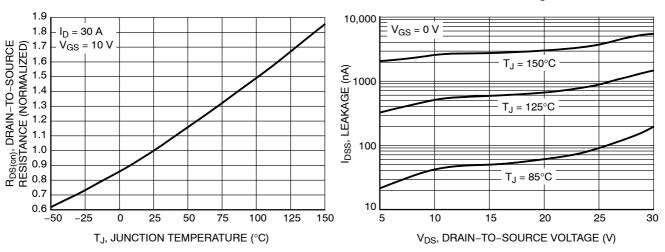


Figure 5. On-Resistance Variation with Figure 6. Drain-to-Source Leakage Current vs. Voltage

4.0

TYPICAL CHARACTERISTICS

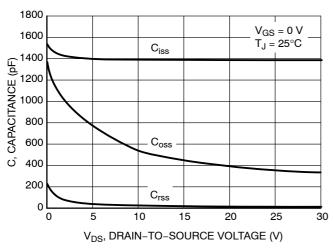


Figure 7. Capacitance Variation

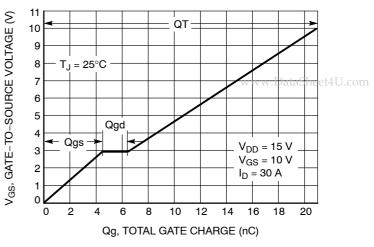


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

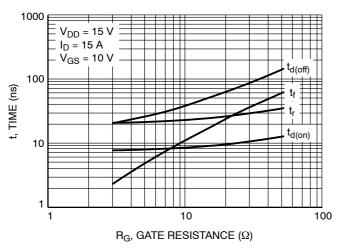


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

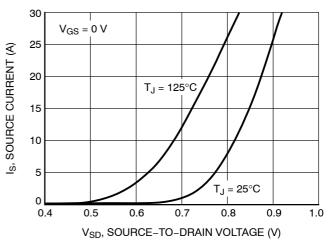


Figure 10. Diode Forward Voltage vs. Current

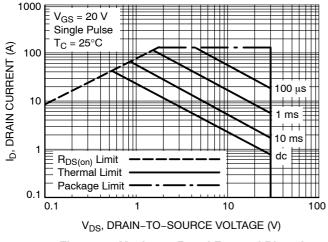


Figure 11. Maximum Rated Forward Biased Safe Operating Area

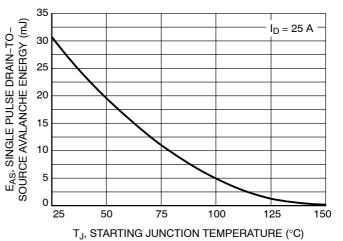


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

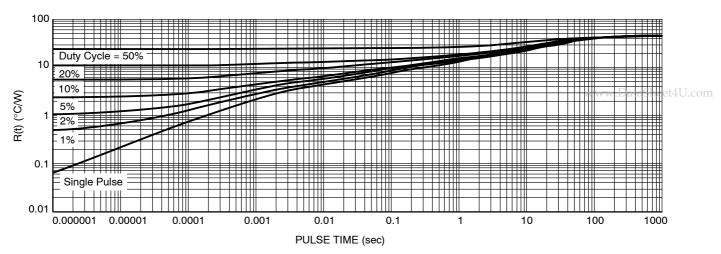


Figure 13. Thermal Response

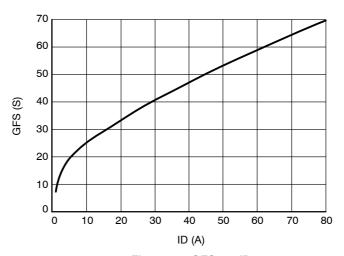
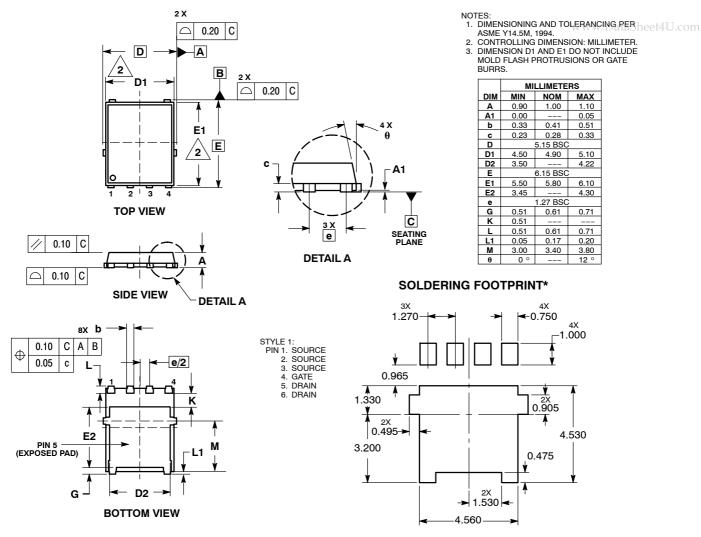


Figure 14. GFS vs. ID

PACKAGE DIMENSIONS

DFN5 5x6, 1.27P (SO8 FL)CASE 488AA-01 ISSUE D



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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